

Fig. 2

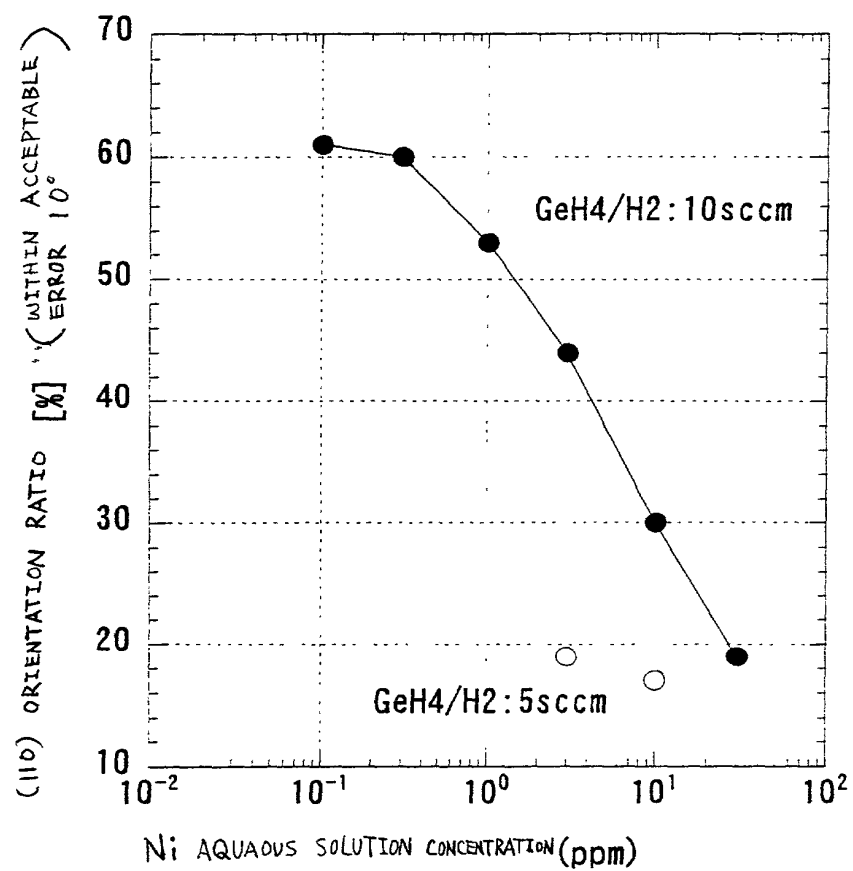


Fig. 3

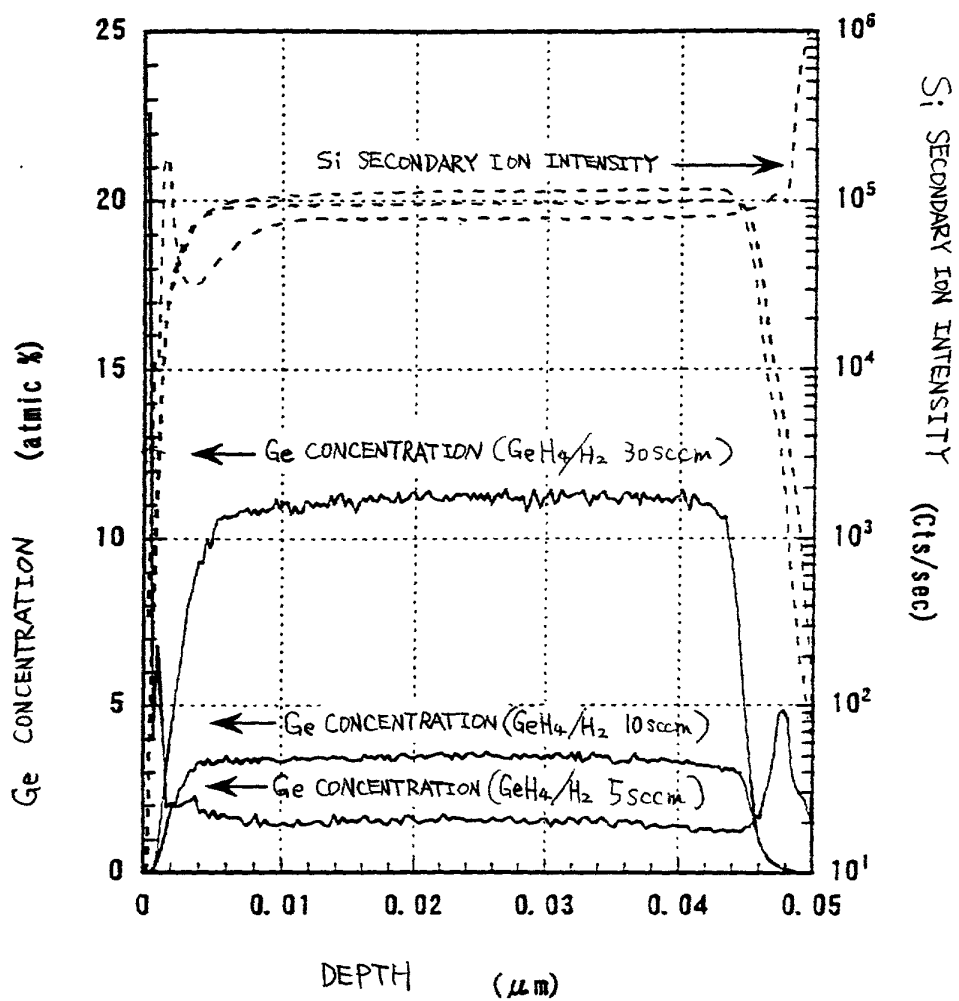


Fig. 4

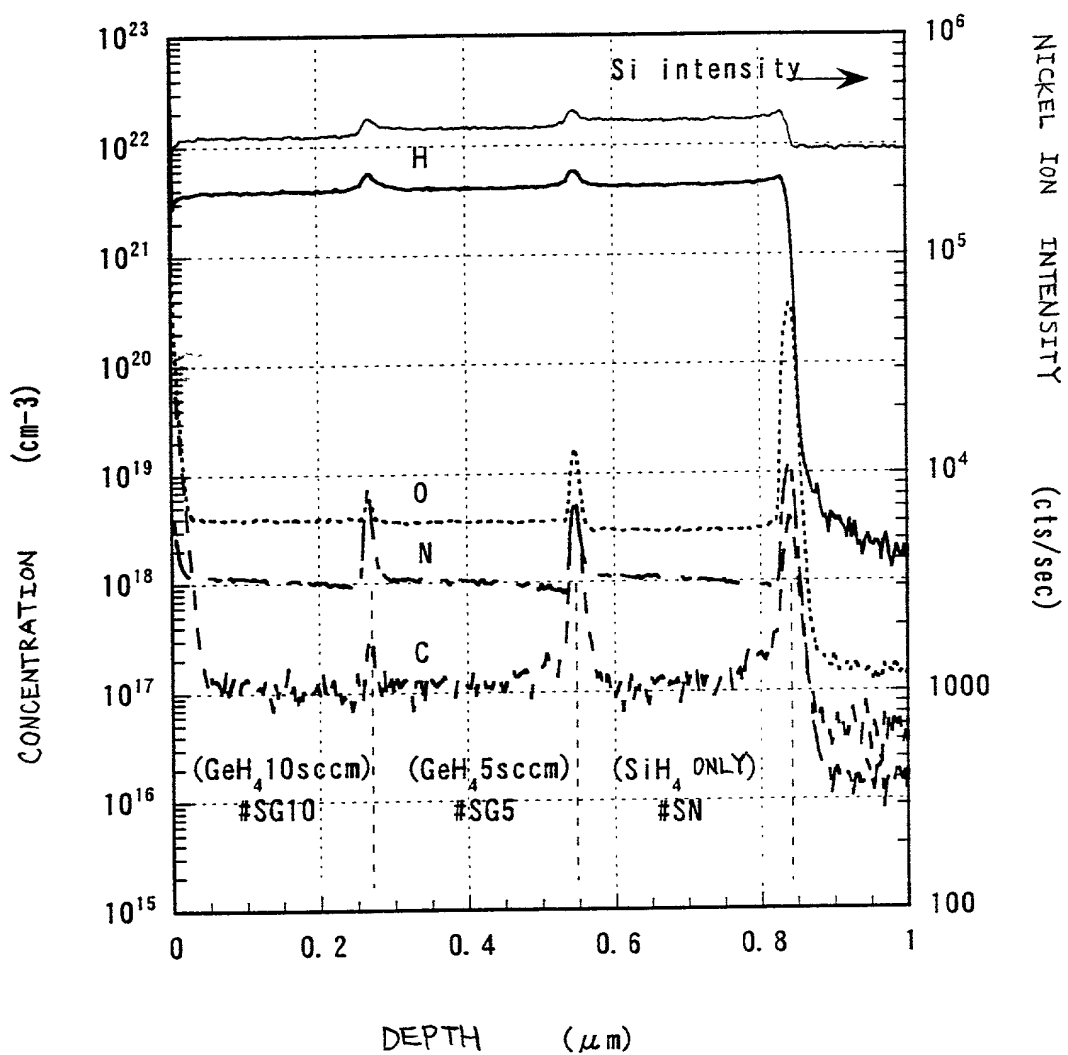
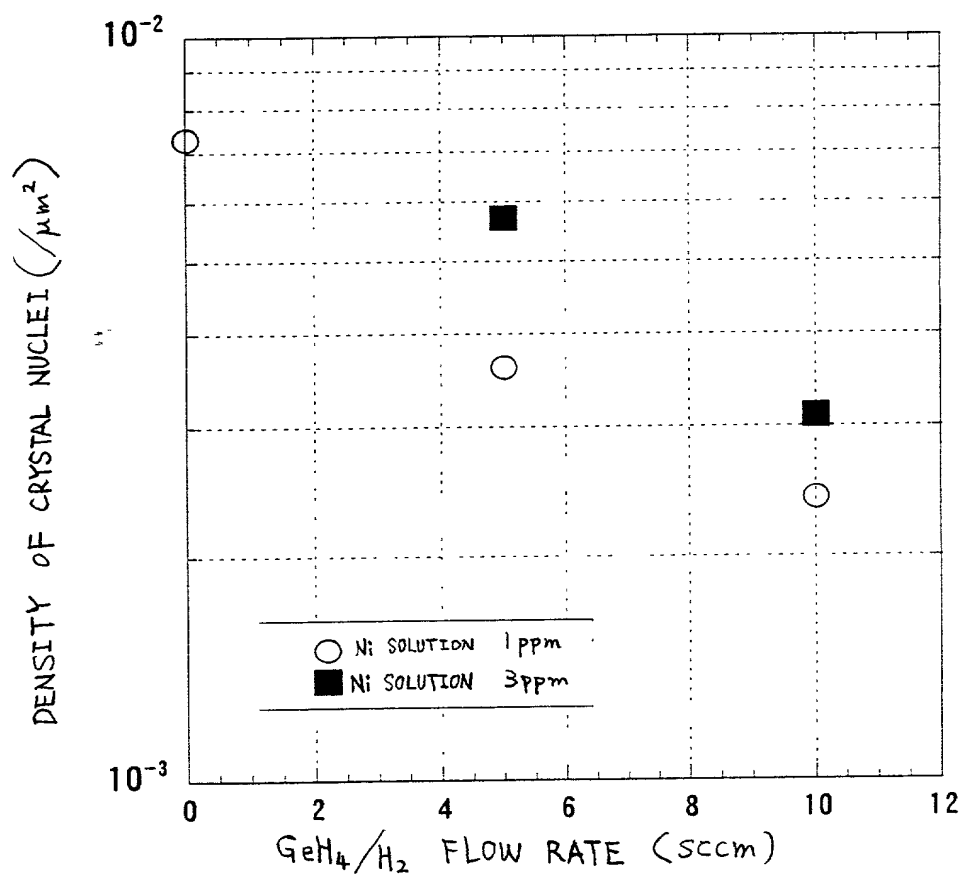
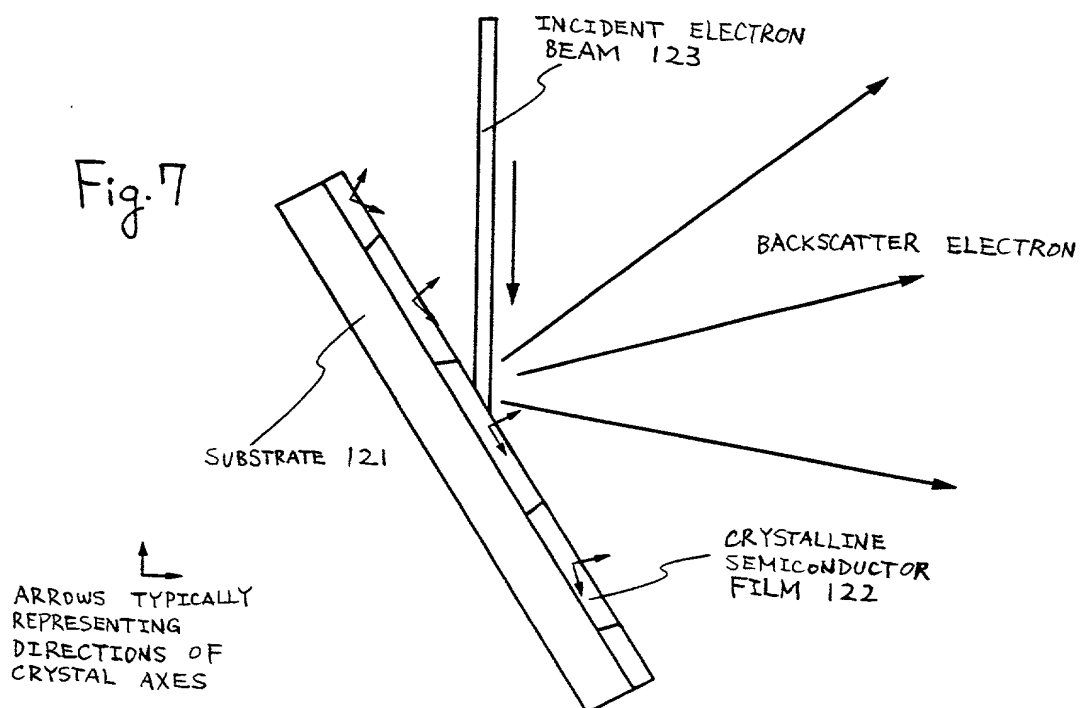
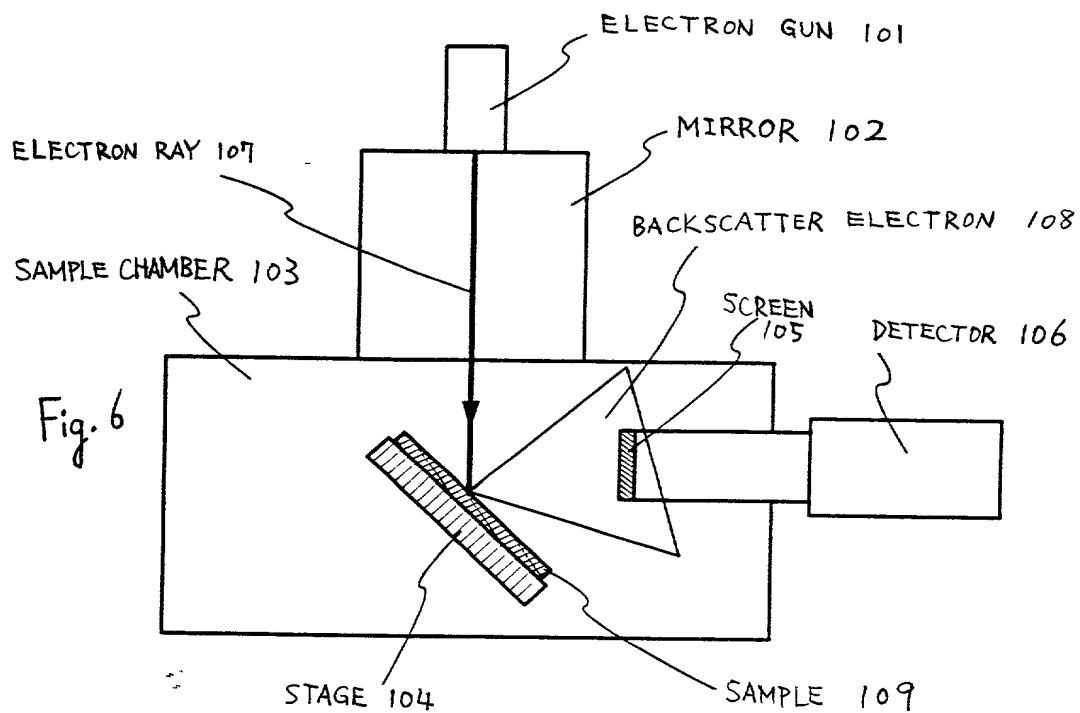


Fig. 5





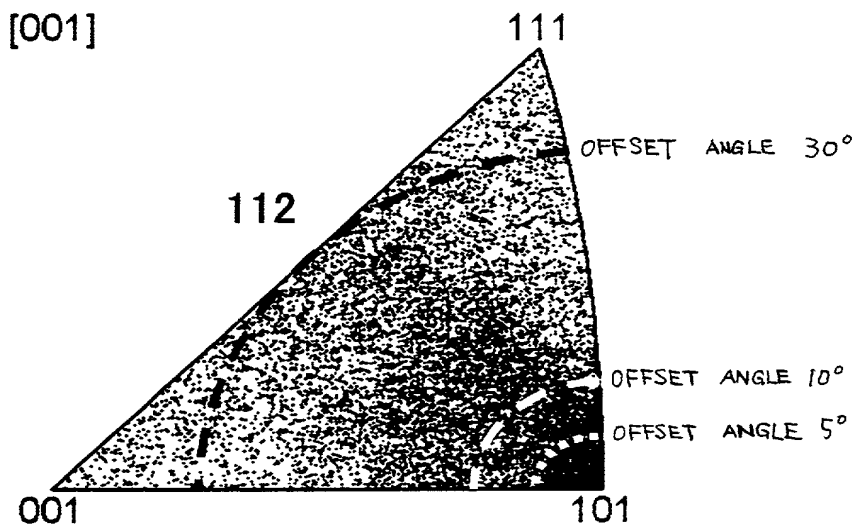


Fig. 8A PLOTS OF ALL OF MEASUREMENT POINTS IN MAPPING MESUREMENT

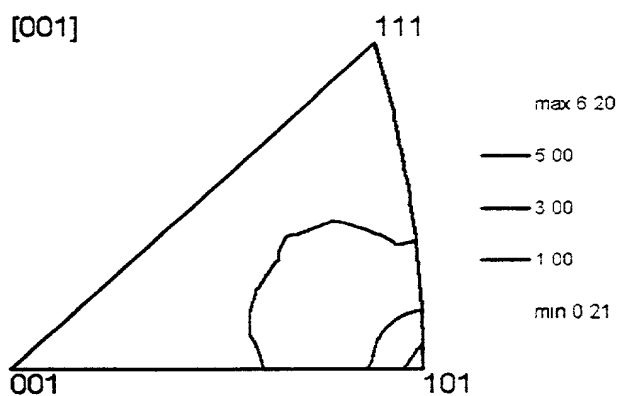
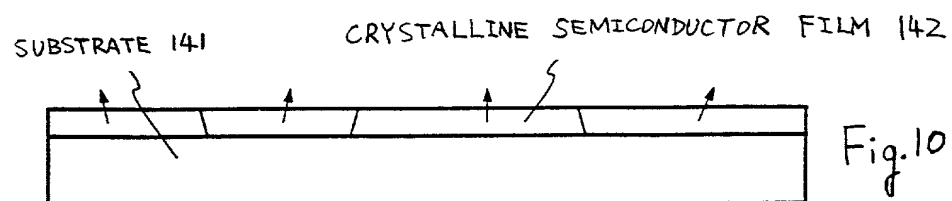
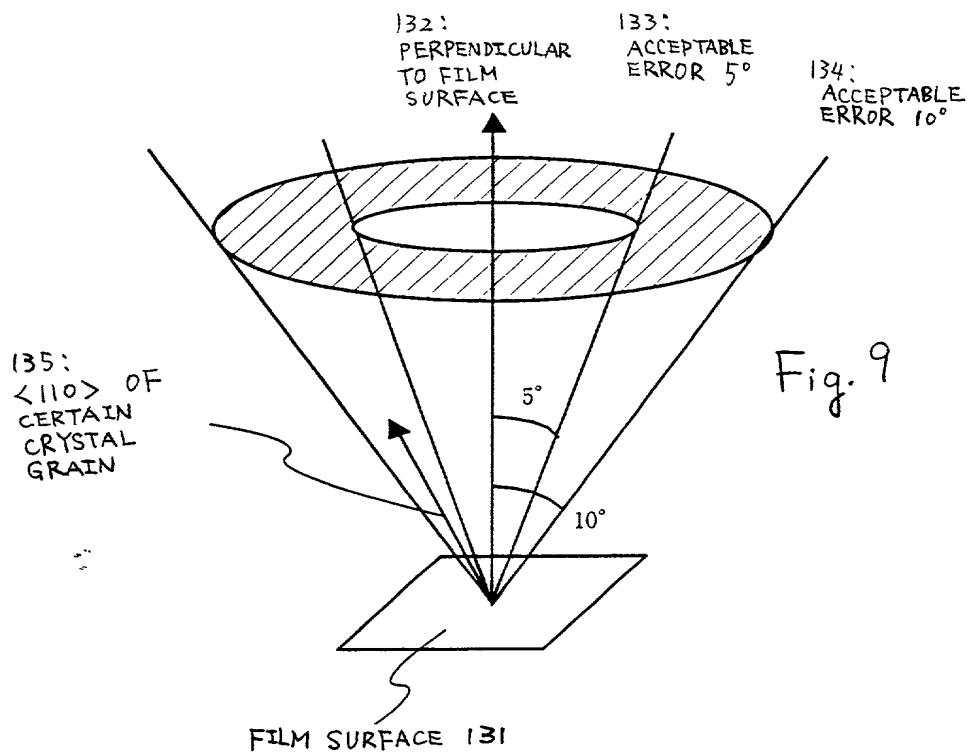


Fig. 8B EXAMPLE OF TRANSLATING CONCENTRATION OF POINTS OF Fig. 8A INTO CONTOUR



VIEW EXPLAINING FLUCTUATION OF  $\langle 101 \rangle$  ORIENTATION OF CRYSTAL GRAIN



Fig. 11A

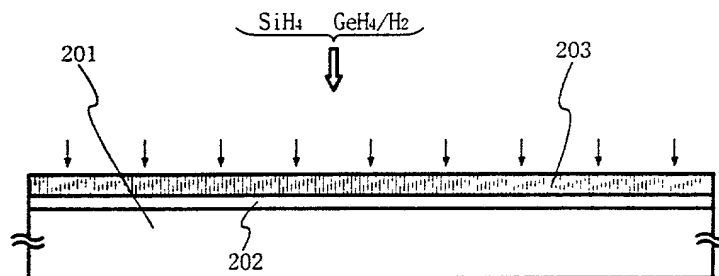


Fig. 11B

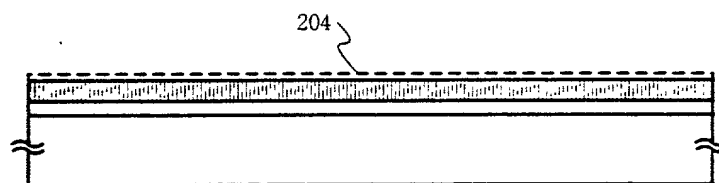


Fig. 11C

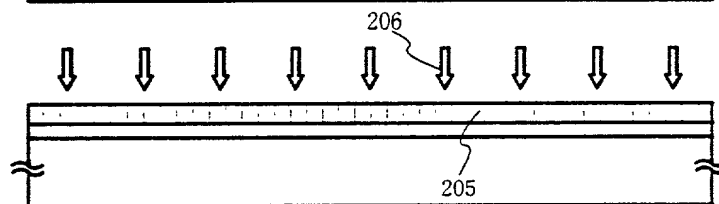
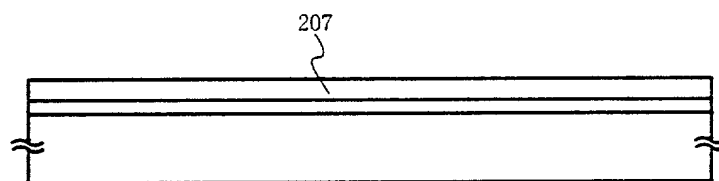
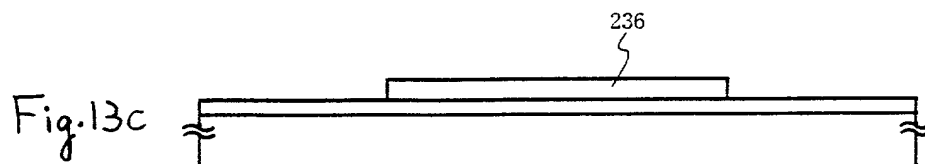
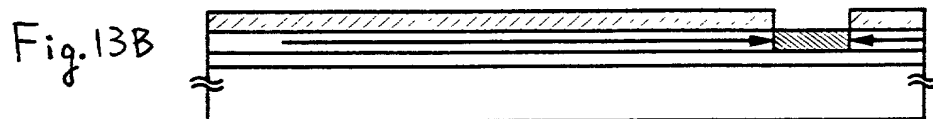
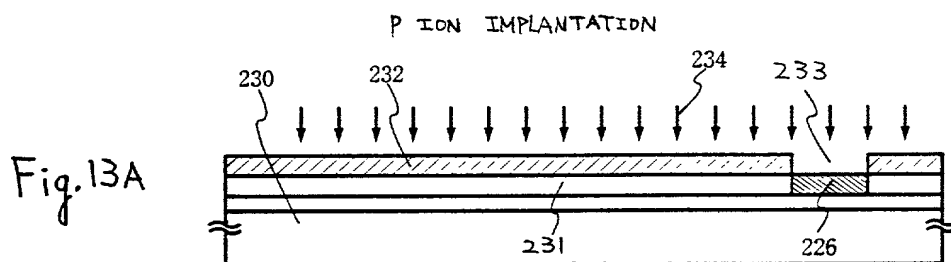
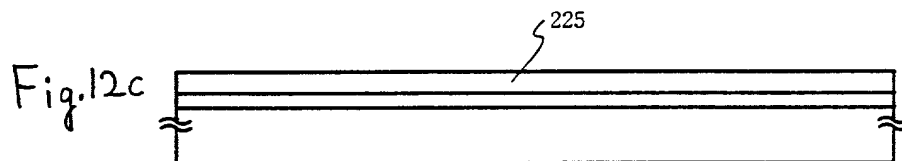
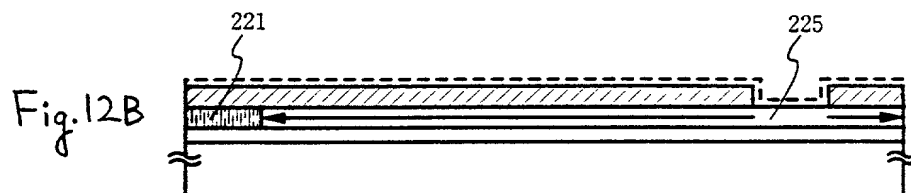
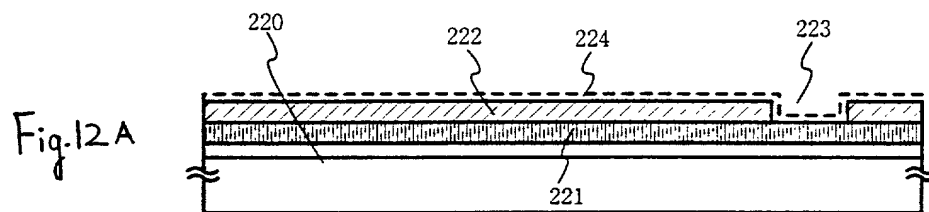
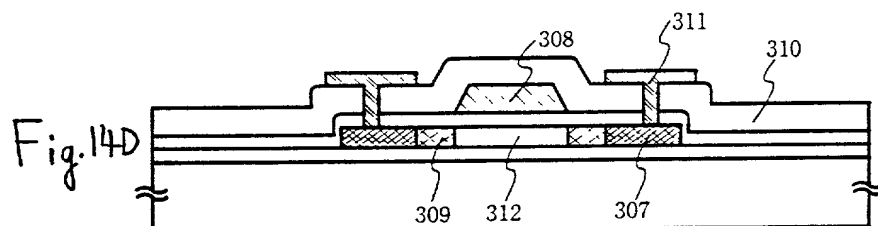
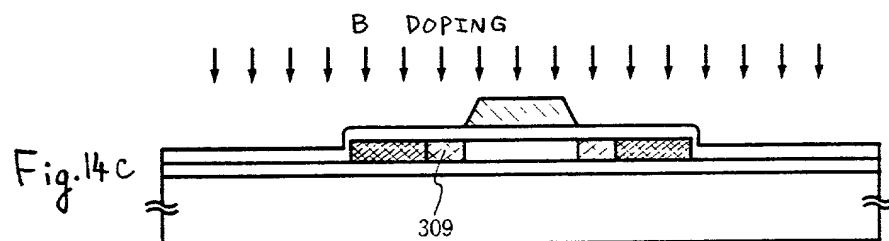
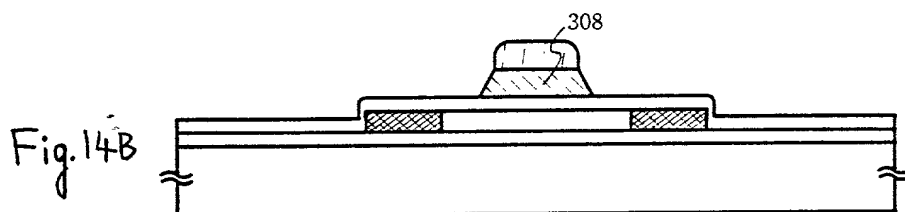
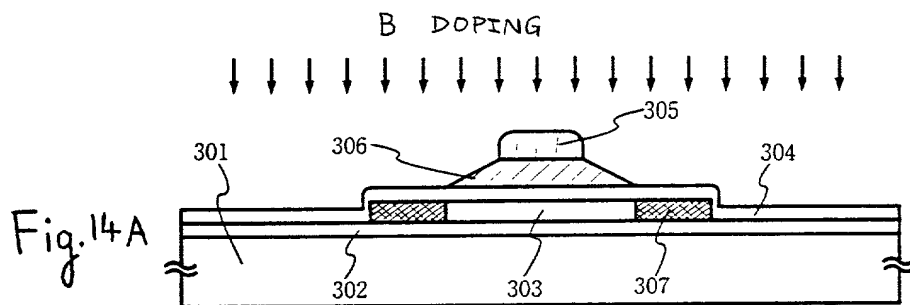


Fig. 11D







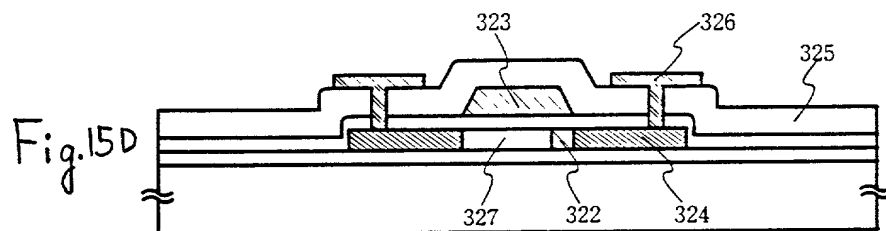
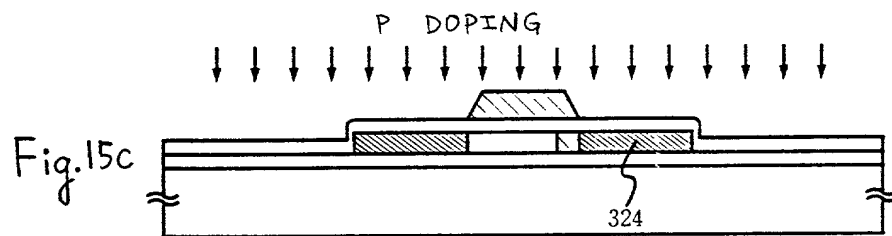
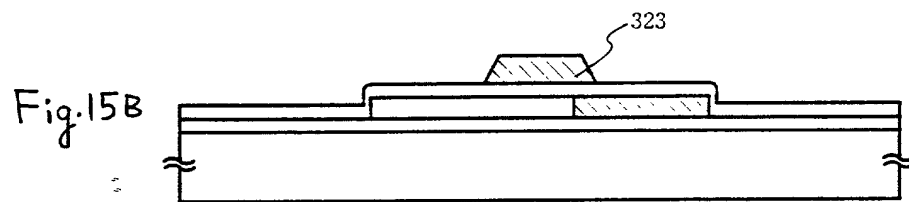
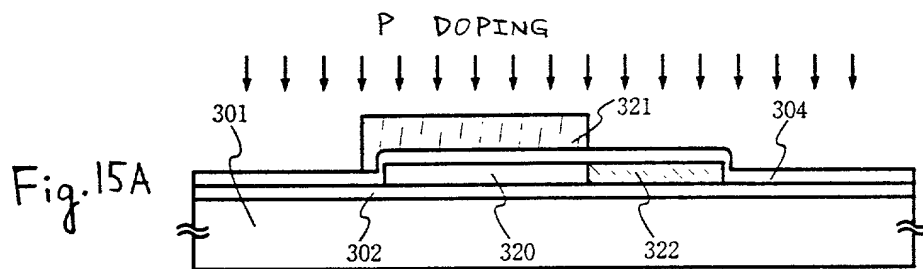


Fig.16A

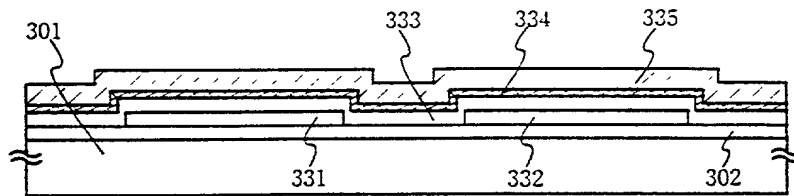


Fig.16B

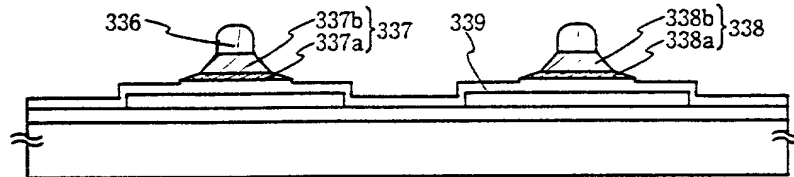


Fig.16C

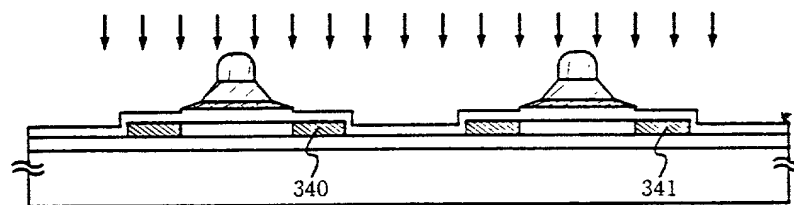


Fig.16D

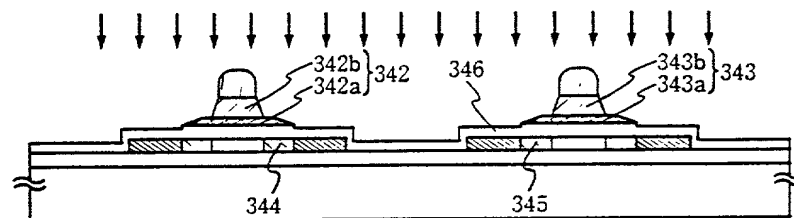


Fig.16E

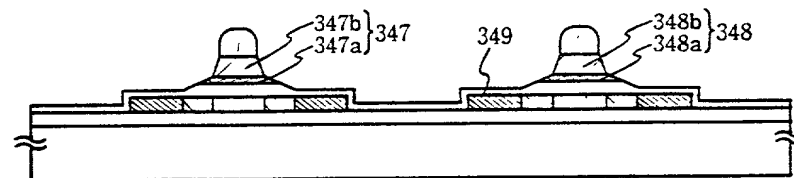


Fig.16F

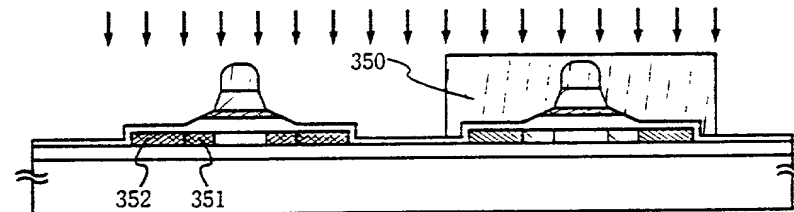


Fig.16G

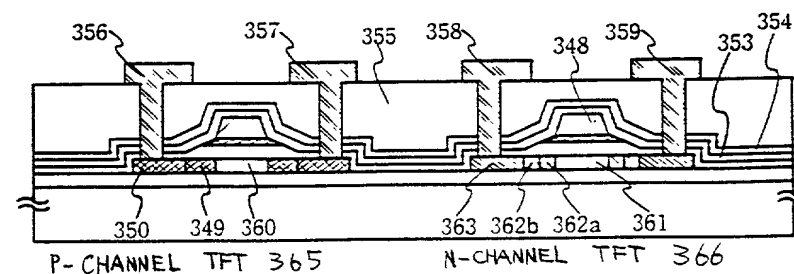


Fig. 17

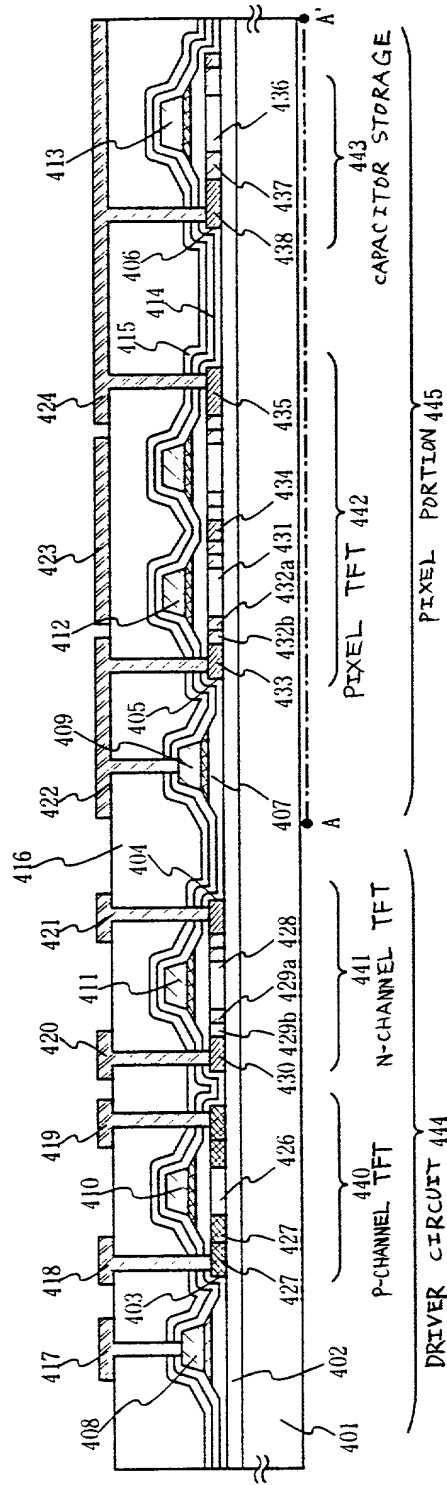
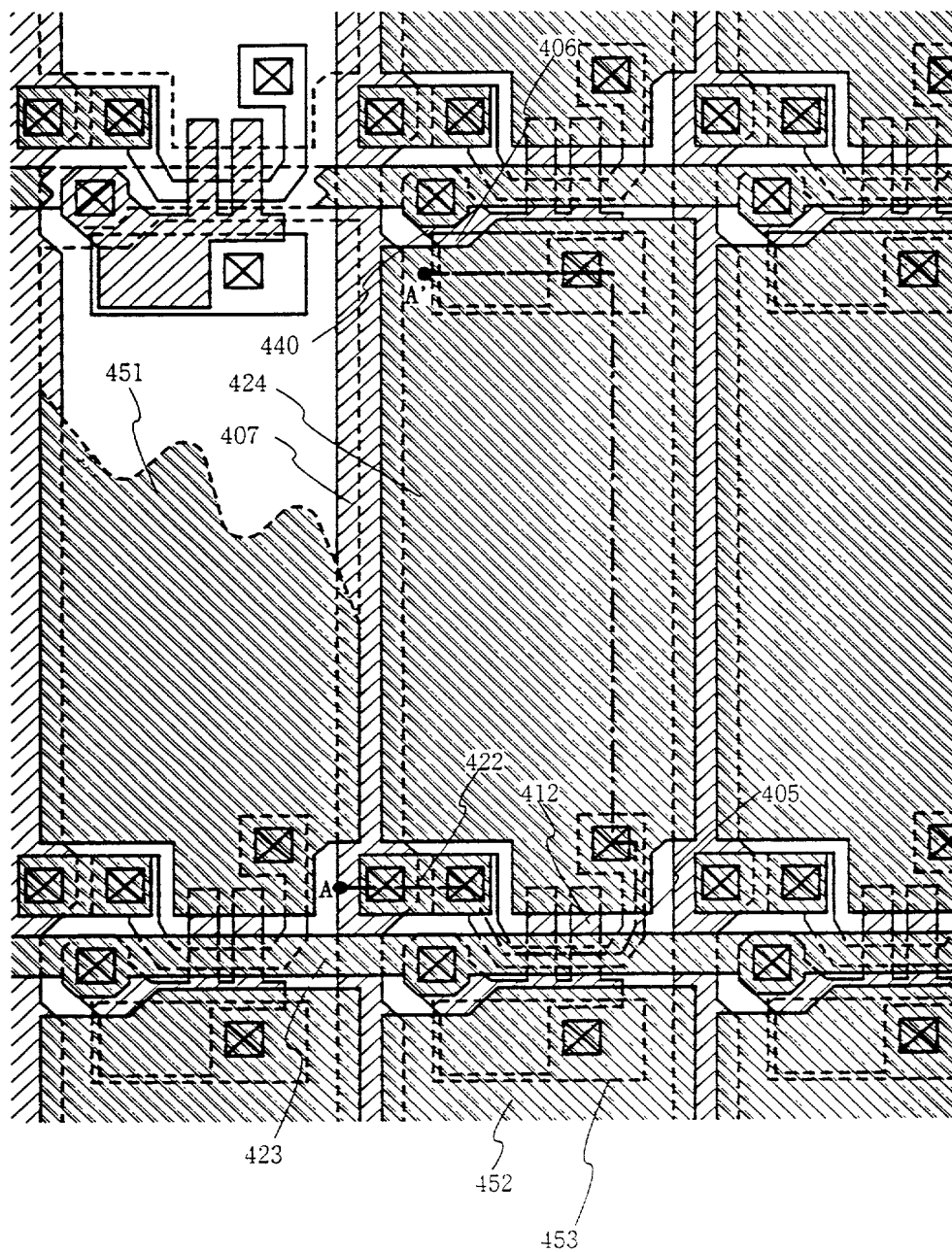


Fig.18



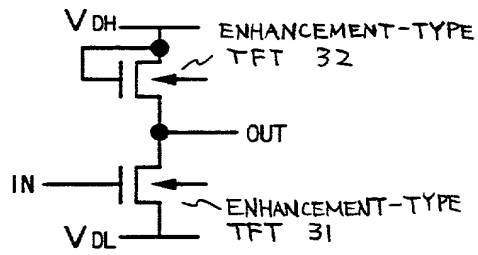


Fig. 19A EEMOS CIRCUIT

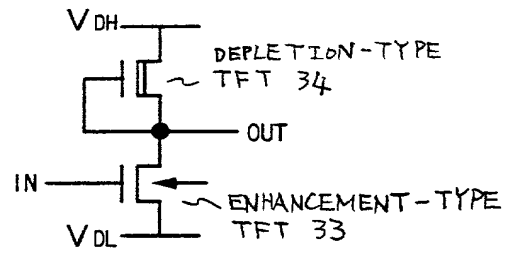


Fig. 19B EDMOS CIRCUIT

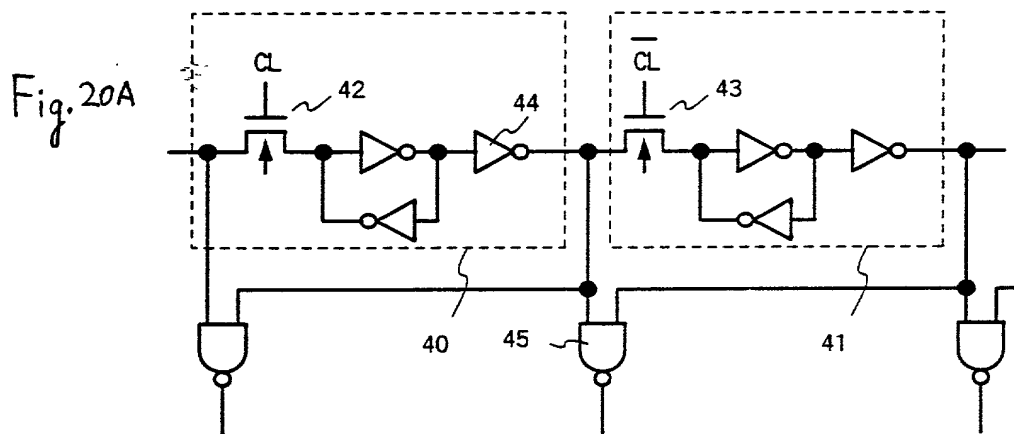
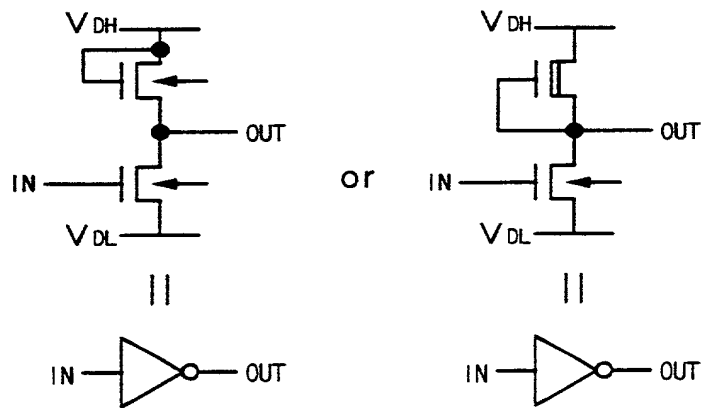


Fig. 20B





DIRECTION OF LIGHT

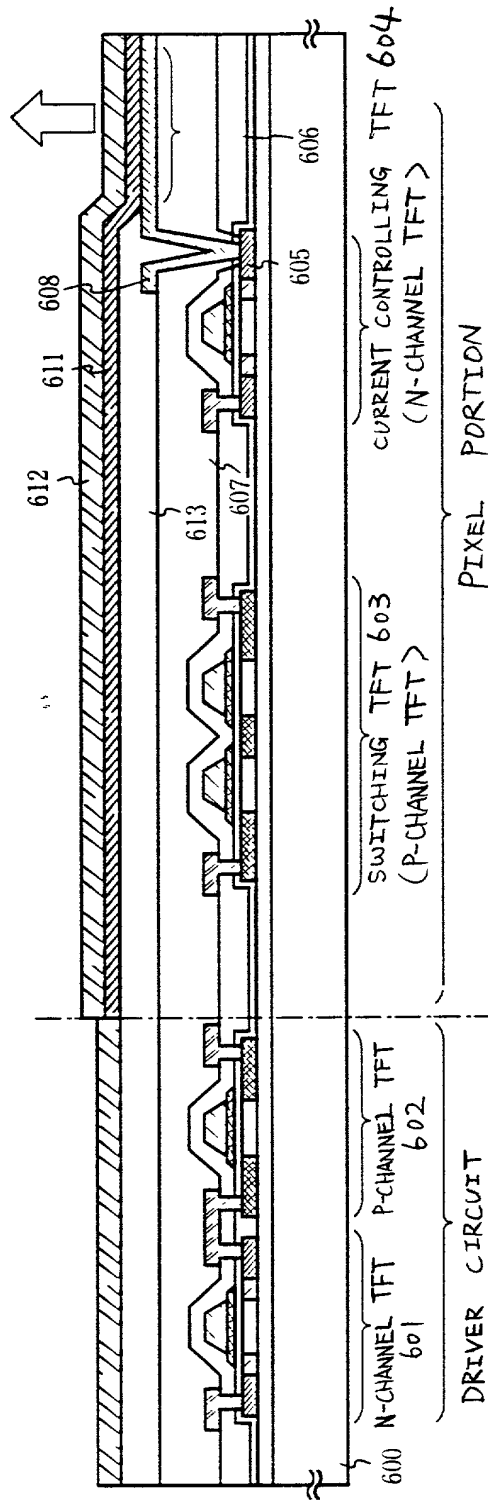


Fig. 21

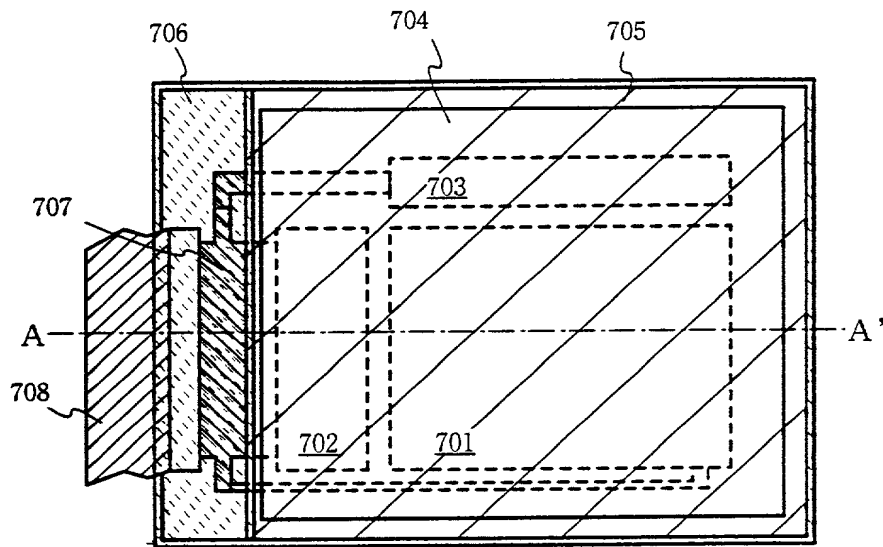


Fig. 22A

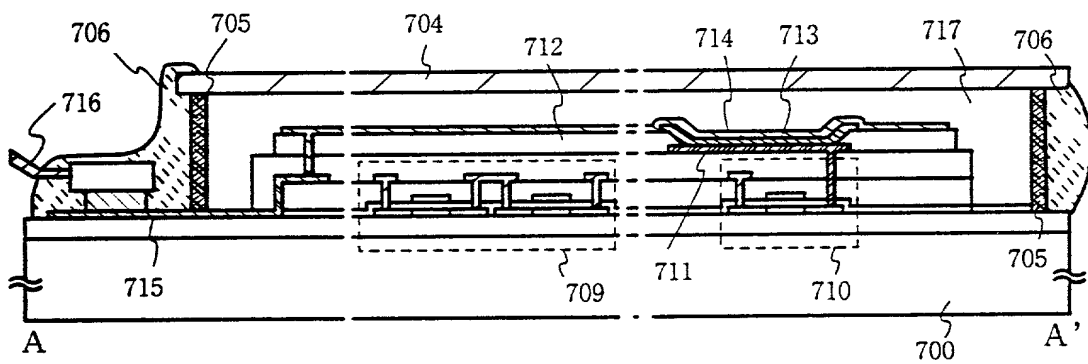


Fig. 22B

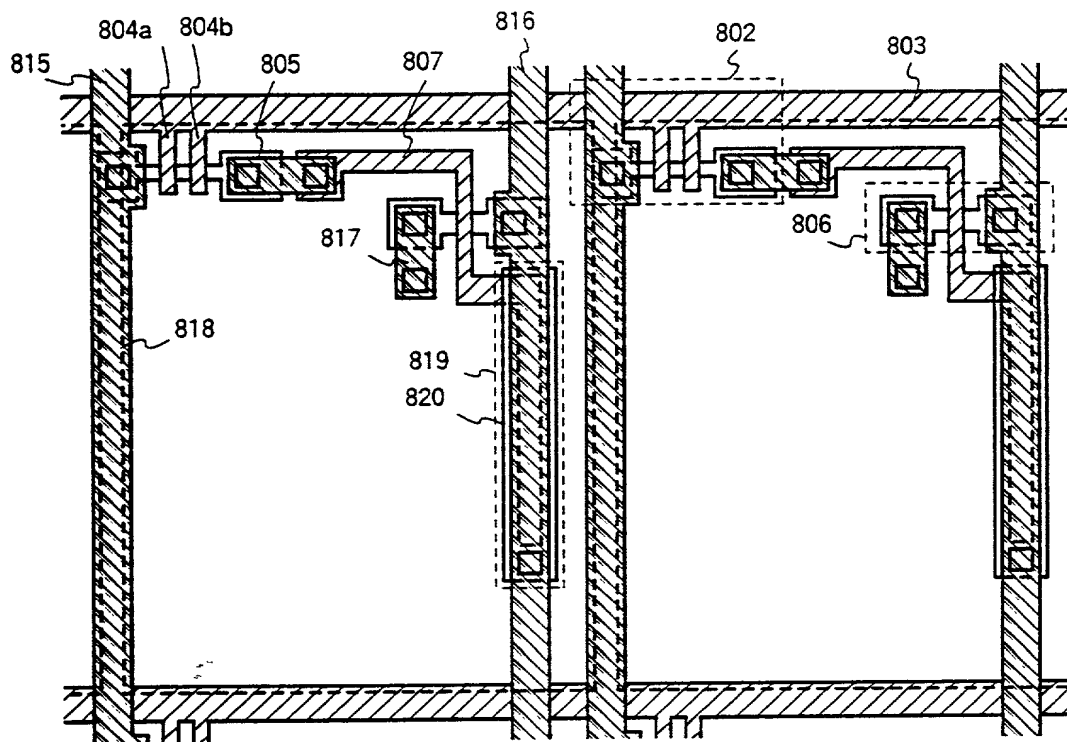


Fig. 23A

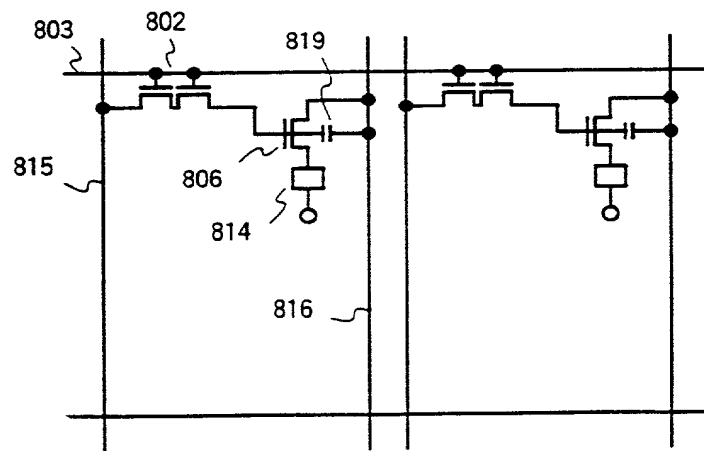


Fig. 23B

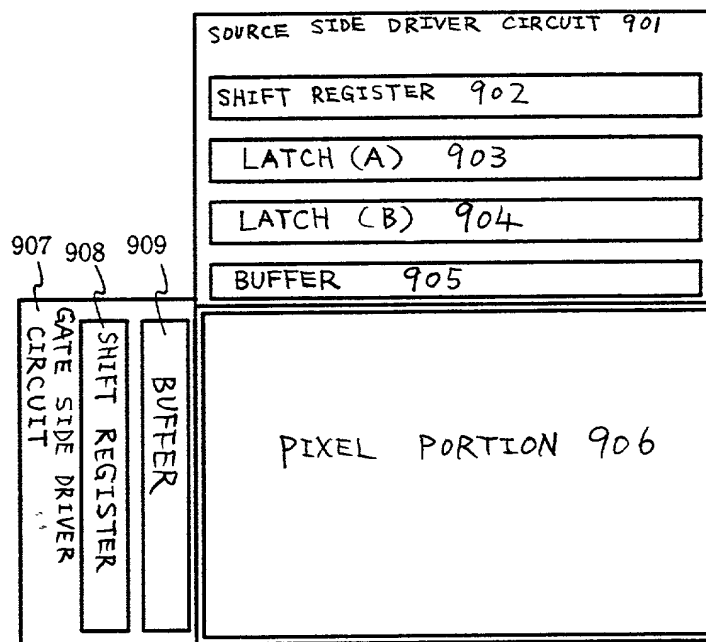


Fig. 24

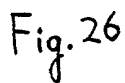
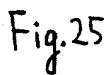
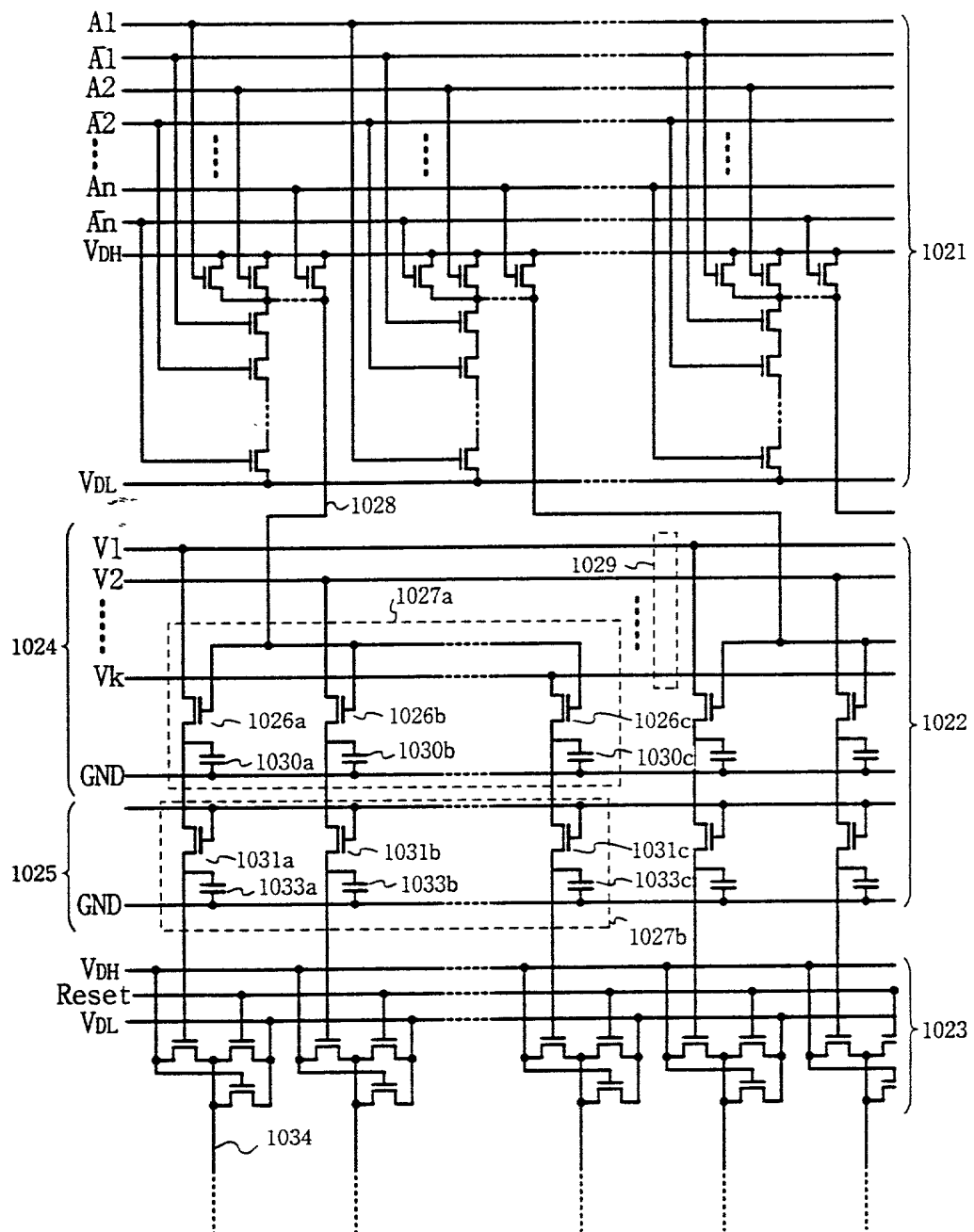
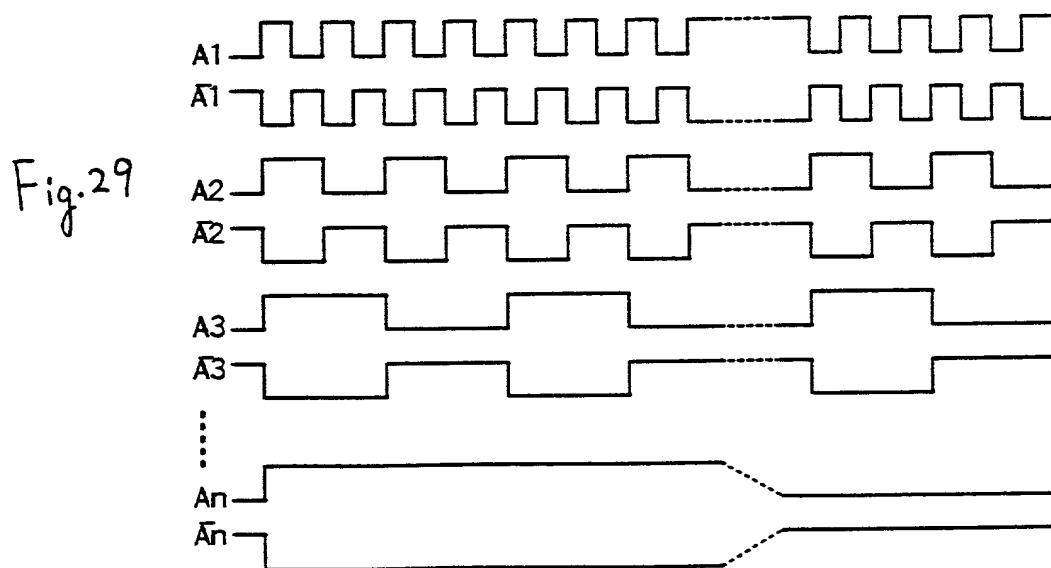
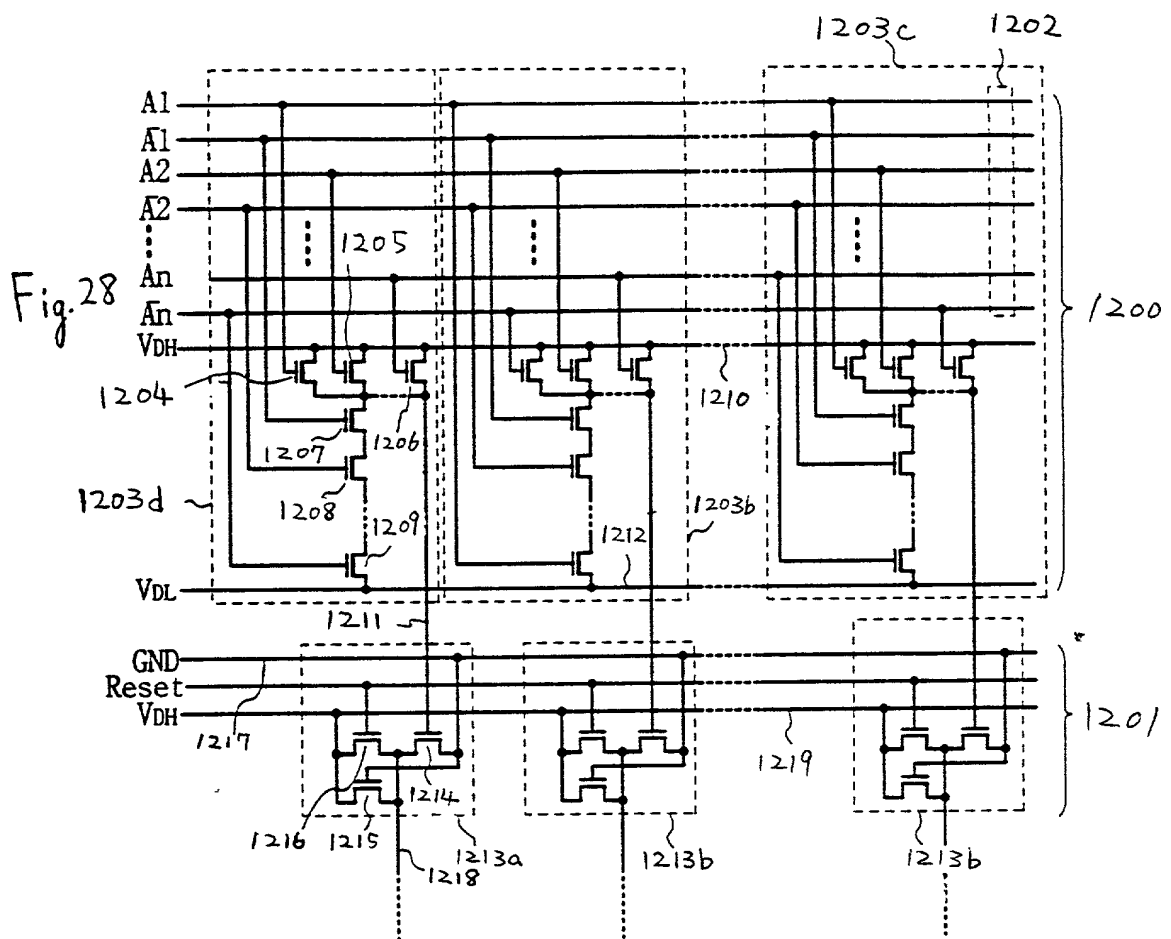


Fig. 27





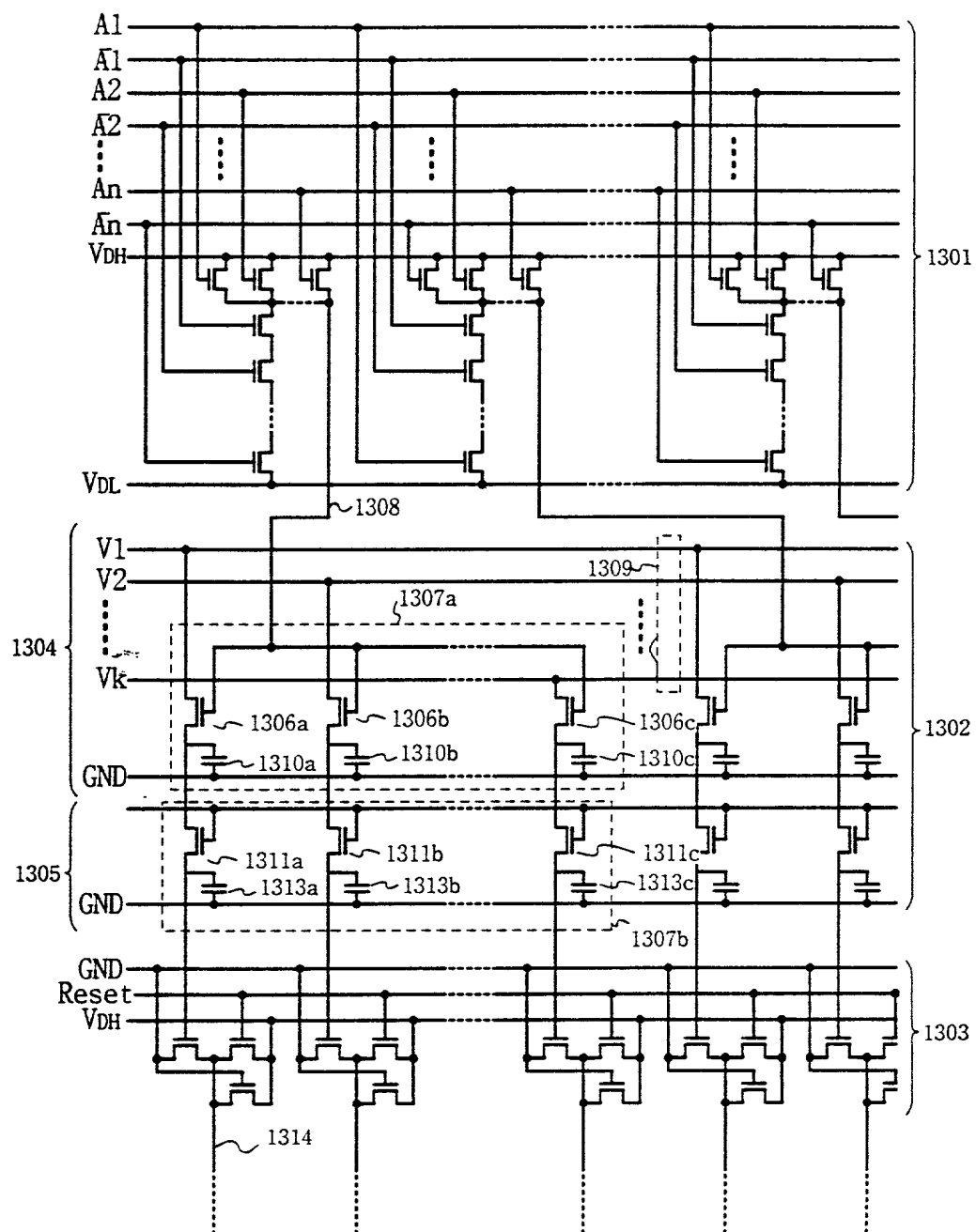
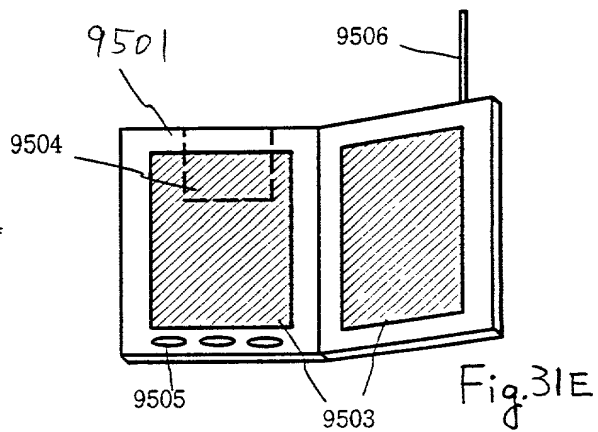
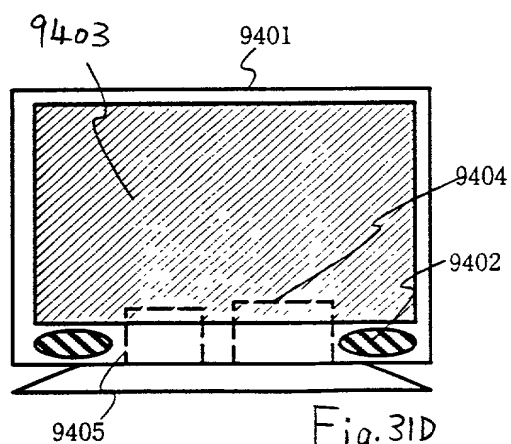
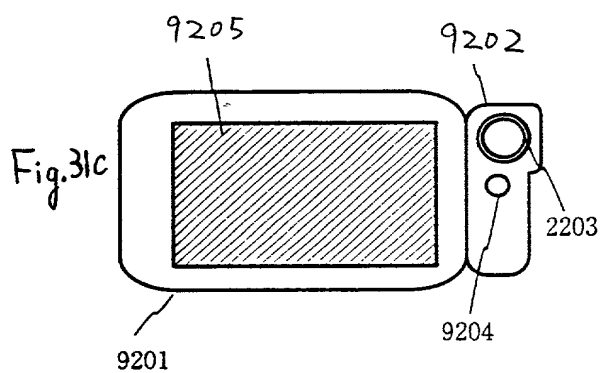
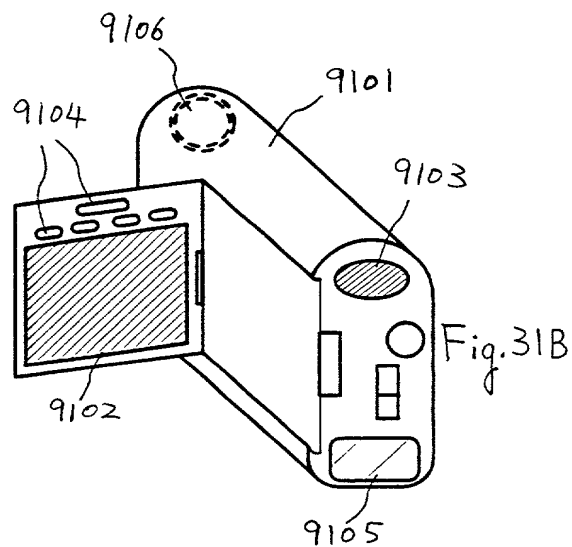
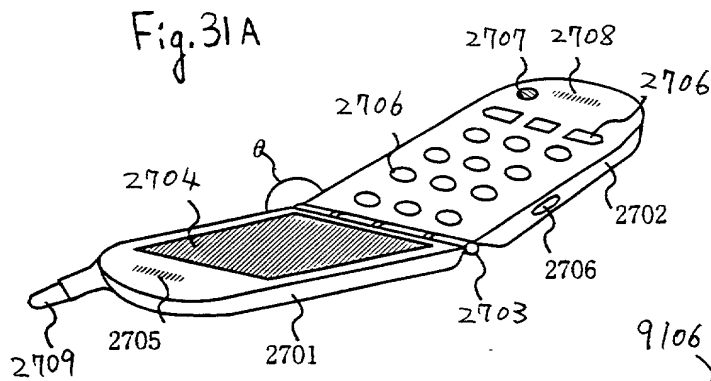
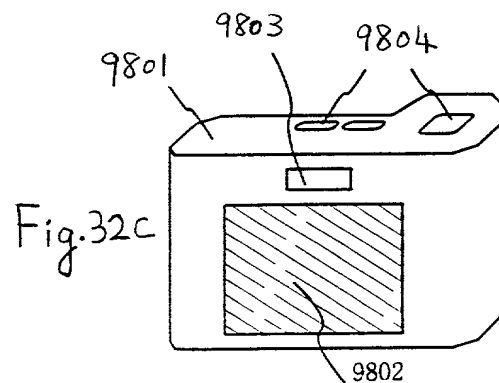
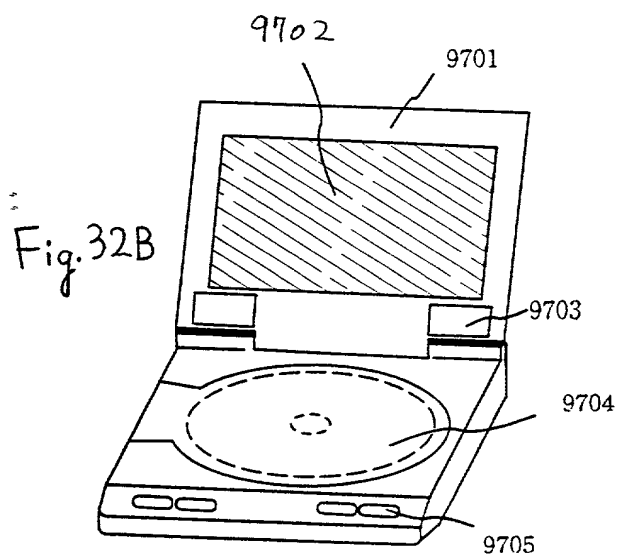
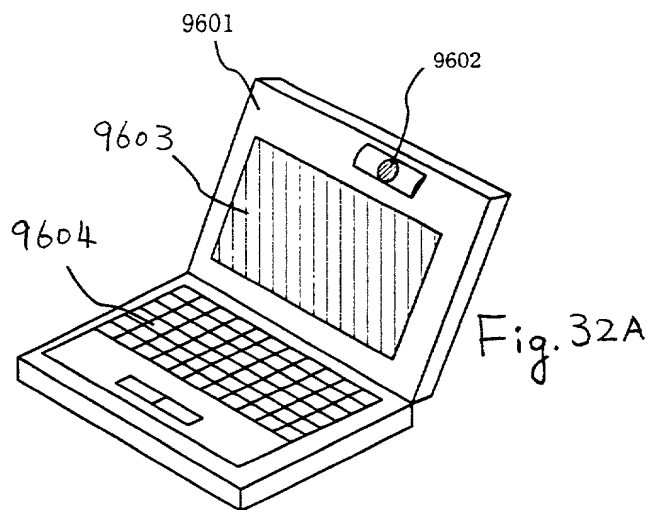
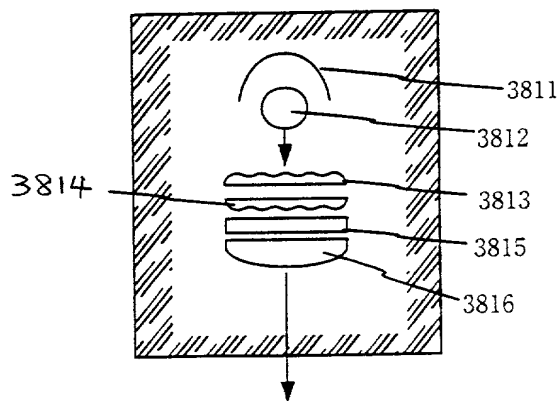
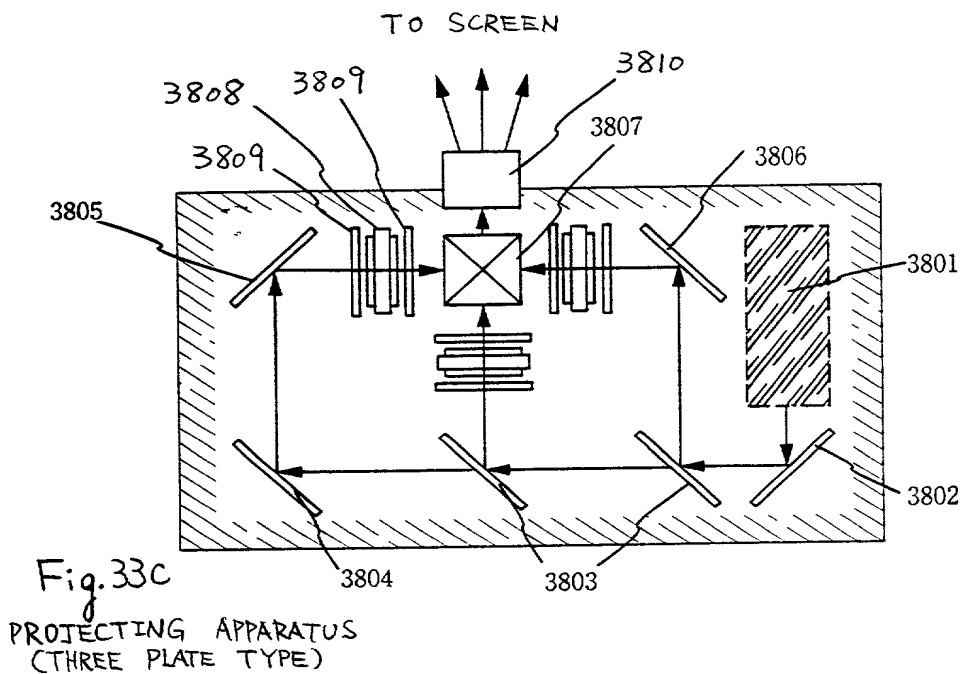
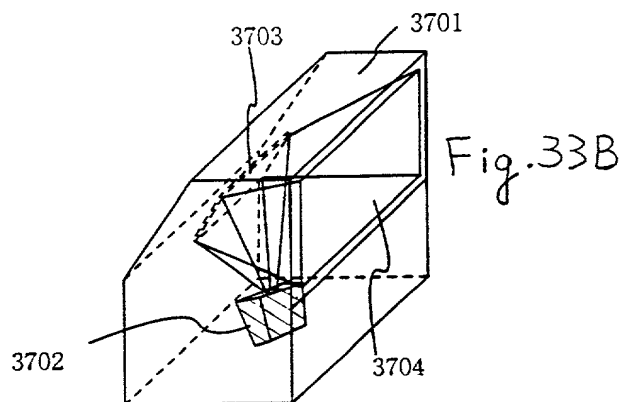
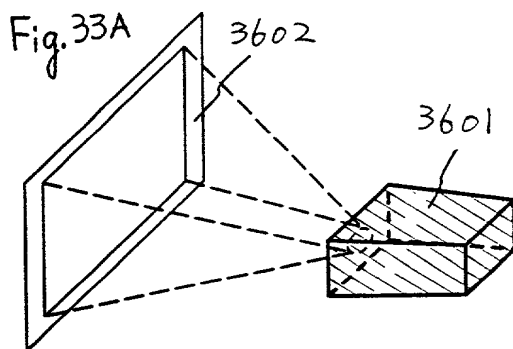


Fig. 30









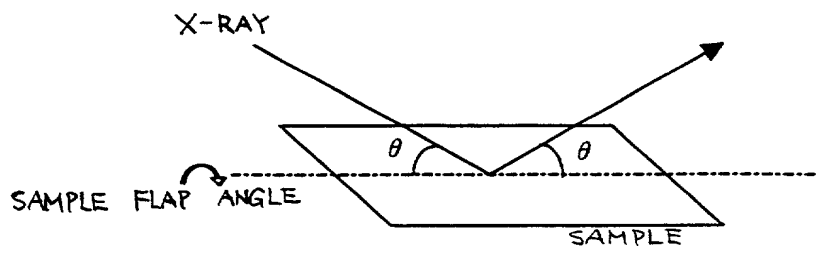


Fig. 34

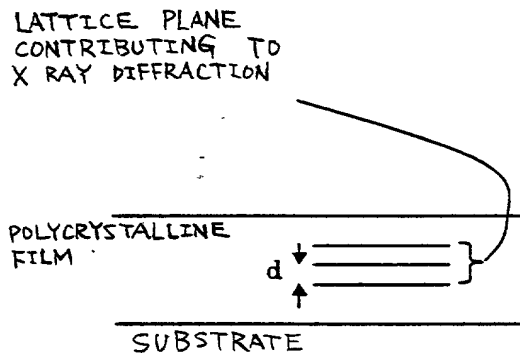


Fig. 35A  
IN CASE OF FLAP ANGLE  $0^\circ$

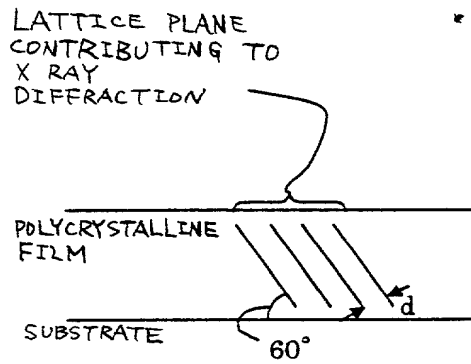


Fig. 35B  
IN CASE OF FLAP ANGLE  $60^\circ$

Fig. 36

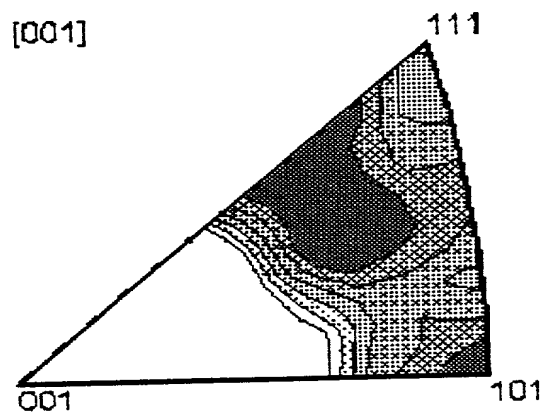


Fig. 37A CRYSTALLIZATION

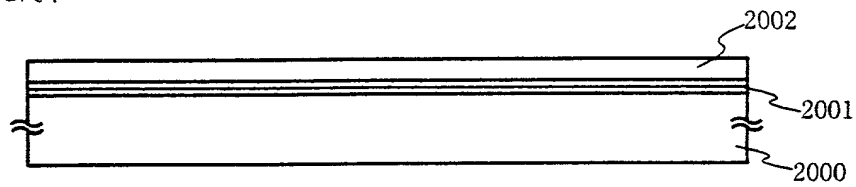


Fig. 37B FORMATION OF BARRIER LAYER AND FORMATION OF SEMICONDUCTOR FILM

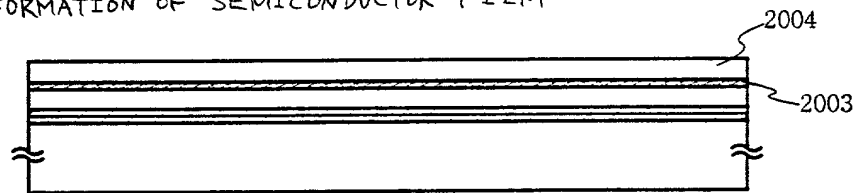


Fig. 37C DOPING WITH NOBLE GAS

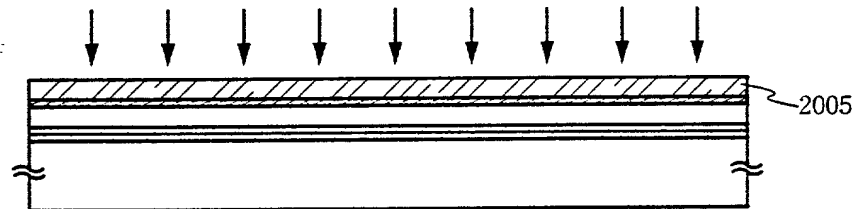


Fig. 37D GETTERING

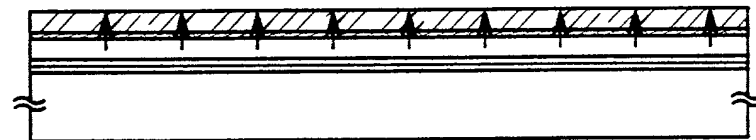
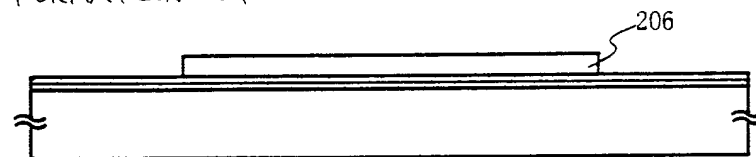


Fig. 37E FORMATION OF SEMICONDUCTOR ISLAND



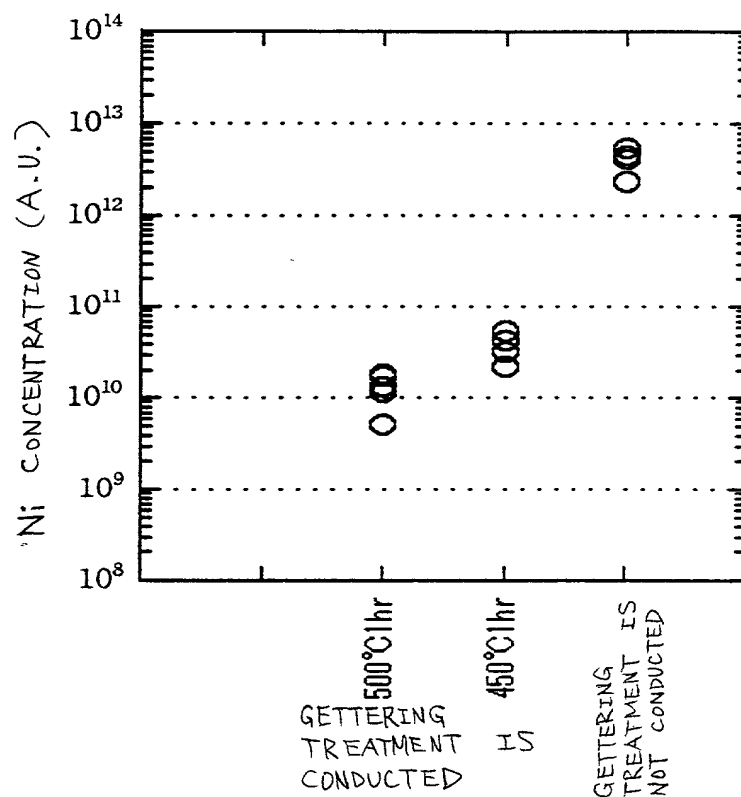


Fig. 38

